

# **SPECIFICATION FOR APPROVAL**



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# **Record of Revision**

Rev	Issue Date	Description	Editor
A0	2024-04-19	Draft	Wang Chun



# 1 General Specifications

	Feature	Spec	Remark
	Screen Size (inch)	3.95	
	Display Mode	AMOLED	
	Display method	Active Matrix TFT	
	Resolution(dot)	1080(H) × 1240(V)	
Diamley Spee	Active Area(mm)	65.448 (W) × 75.144 (H)	
Display Spec	Pixel Pitch (um)	0.0606(H) × 0.0606(V)	
	Pixel Configuration	V-Style4	
	Technology Type	LTPS	
	Color Depth	16.7M	
	Interface	MIPI 4 LANE	
	Polarizer Surface Treatment	НС	2H
Mechanical	With TP/Without TP	Without TP	
Characteristics	Module Outline Dimension(W x H x D) (mm)	67.25mm*79.87mm*0.8mm	
	Driver IC(Type)	CH13726A	
Electronic	Touch IC(Type)	NC	
	Frame Rate	60HZ	

Note 1: Requirements on Environmental Protection: RoHS2.0.



# 2 Input/output Terminals

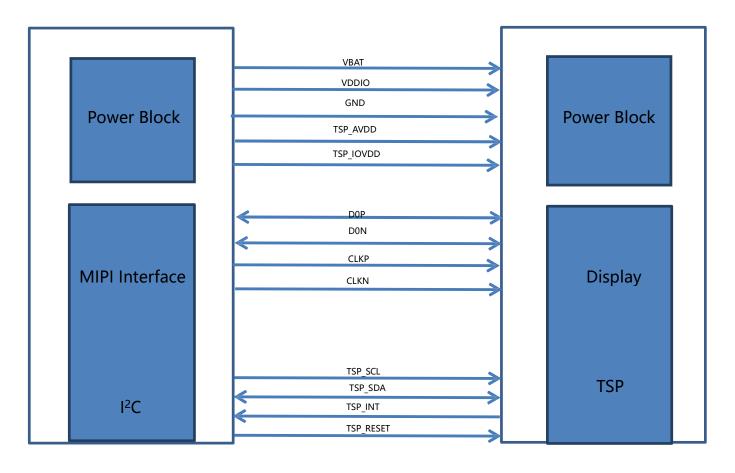
# 2.1 Main FPC Pin Assignment

	G2,G3,G6	GND	
19	TSP_SDA	20	VCI
18	TSP_SCL	21	TSP_AVDD
17	TSP_RESET	22	TSP_VDDIO
16	GND	23	TSP_INT
15	D3N	24	AVDD_EN
14	D3P	25	SWIRE
13	GND	26	TE
12	D2N	27	RSTB
11	D2P	28	VDDIO
10	GND	29	ELVSS
9	CLKN	30	ELVSS
8	CLKP	31	ELVSS
7	GND	32	ELVDD
6	D1N	33	ELVDD
5	D1P	34	ELVDD
4	GND	35	MTP_PWR(NC)
3	D0N	36	AVDD
2	D0P	37	ID(NC)
1	GND	38	ERR_FG
	G1,G4,G5	GND	

Note: I=Input; O=Output; P=Power; I/O=Input / Output



# 2.2 MCU and Display Module Interface Conflagration





# 3 Absolute Maximum Ratings

## 3.1 Driving AMOLED Panel

Maximum Ratings (Voltage Referenced to VSS) VSS=0V, Ta=25°C

Item	Symbol	MIN	MAX	Unit
Analog Power supply	VCI	-0.3	+5.5	V
Logic Power supply	VDDIO	-0.3	+5.5	V
Analog Power supply	AVDD	-0.3	8.8	V
Positive power for OLED	ELVDD	+4.0	+5.0	V
Negative power for OLED	ELVSS	-1.0	-5.0	V

Note: Functional operation should satisfy the limits in the Electrical Characteristics tables or Pin Description section. If the module exceeds the absolute maximum ratings, permanent damage may occur. Besides, if the module is operated with the absolute maximum ratings for a long time, the reliability may also drop.

#### 4 Electrical Characteristics

## 4.1 Driving AMOLED Panel

Ta=25℃

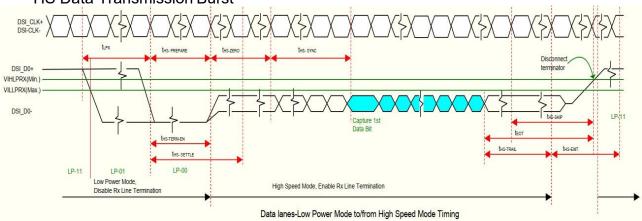
Item		Symbol	MIN	TYP	MAX	Unit
Logic Power supply		VDDIO	1.65	1.80	1.98	V
Analog Power supply		VCI	2.5	3.0	3.60	V
Analog Power supply		AVDD	4.5	6.5	6.5	٧
Default Positive Outpu	ELVDD	4.55	4.60	4.65	V	
Positive Output voltage	LLVDD	-0.80	-	+0.80	%	
Default Negative Outpu	ıt voltage	ELVSS	-1.00	-3.00	-4.00	V
Negative output voltag	e total variation	LLV33	-1.00	-	+1.00	%
Input Signal Voltage	High Level	VIH	0.70*VDDIO	-	VDDIO	V
Imput signal voltage	Low Level	VIL	0.00	-	0.70*VDDIO	V
Output Signal Voltage	High Level	VOH	0.80*VDDIO	-	VDDIO	V
Output Signal Voltage	Low Level	VOL	0.00	-	0.20*VDDIO	V

Note: The current and power consumption were tested under White pattern,  $25^{\circ}$ C

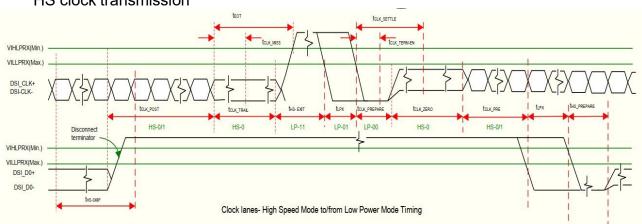


# 5 AC Characteristics

# 5.1 MIPI Interface Characteristics HS Data Transmission Burst



#### HS clock transmission



**Timing Parameter:** 



Signal	Symbol	Parameter	Min.	Тур.	Max.	Unit	Description
Low Power N	Node to High S	peed Mode Timing			28 3		
DSI-Dn+/-	t <sub>LPX</sub>	Length of any low power state period	50	-	-	ns	Input
DSI-Dn+/-	t <sub>HS-PREPARE</sub>	Time to drive LP-00 to prepare for HS transmission	40+4×UI	-	85+6×UI	ns	Input
DSI-Dn+/-	t <sub>HS-TERM-EN</sub>	Time to enable data receiver line termination measured from when Dn crosses VILMAX	-	-	35+4×UI	ns	Input
High Speed	Mode to Low P	ower Mode Timing					
DSI-Dn+/-	ths-skip	Time-out at display module to ignore transition period of EoT	40	-	55+4×UI	ns	Input
DSI-Dn+/-	t <sub>HS-EXIT</sub>	Time to drive LP-11 after HS burst	100	=	-	ns	Input
DSI-Dn+/-	ths-trail	Time to drive flipped differential state after last payload data bit of a HS transmission burst	60+4×UI	-	-	ns	Input
High Speed	Mode to/from L	ow Power Mode timing					
DSI-CLK+/-	t <sub>CLK-POS</sub>	Time that the MPU shall continue sending HS clock after the last associated data lane has transition to LP mode	60+52×UI	-	-	ns	Input
DSI-CLK+/-	t <sub>CLK</sub> -TRAIL	Time to drive HS differential state after last payload clock bit of a HS transmission burst	60	-		ns	Input
DSI-CLK+/-	t <sub>HS-EXIT</sub>	Time to drive LP-11 after HS burst	100	9	-	ns	Input
DSI-CLK+/-	t <sub>CLK-PREPARE</sub>	Time to drive LP-00 to prepare for HS transmission	38	2	95	ns	Input
DSI-CLK+/-	t <sub>CLK-TERM-EN</sub>	Time-out at clock lane display module to enable HS transmission	9 <del>7</del> %	-	38	ns	Input
DSI-CLK+/-	tclk-prepare +tclk-zero	Minimum lead HS-0 drive period before starting clock	300	-	-	ns	Input
DSI-CLK+/-	t <sub>CLK-PRE</sub>	Time that the HS clock shall be driven prior to any associated data lane beginning the transition from LP to HS mode	8×UI	-	-	ns	Input

Note 1: VDDIO/VDDAM/VDDR =1.65~3.6V, VCI=2.5 to 3.6V, VSSIO=DVSS=VSSA=VSSAM=VSSR =VSSB=0V, Ta=-30 to +85  $^{\circ}$ C.

Note 2: Dn=D0, D1, D2 and D3.

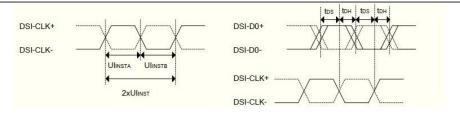
#### High Speed Mode:

Signal	Symbol	Parameter	Min.	Тур.	Max.	Unit	Description
DSI-CLK+/-	2×UI <sub>INST</sub>	Double UI instantaneous	1.66	-	TBD	ns	
DSI-CLK+/-	UI <sub>INSTA</sub> UI <sub>INSTB</sub>	UI instantaneous halves (UI = Ulinsta = Ulinsta)	0.83	128	TBD	ns	
DSI-Dn+/-	t <sub>DS</sub>	Data to clock setup time	0.15×UI		) <b>-</b>	ps	
DSI-Dn+/-	t <sub>DH</sub>	Data to clock hold time	0.15×UI	-	1:-	ps	
DSI-CLK+/-	tortclk	Differential rise time for clock	150	- 1	0.3×UI	ps	
DSI-Dn+/-	t <sub>DRTDATA</sub>	Differential rise time for data	150		0.3×UI	ps	
DSI-CLK+/-	t <sub>DFTCLK</sub>	Differential fall time for clock	150	12.6	0.3×UI	ps	
DSI-Dn+/-	t <sub>DFTDATA</sub>	Differential fall time for data	150	( <u>1</u> 2)	0.3×UI	ps	

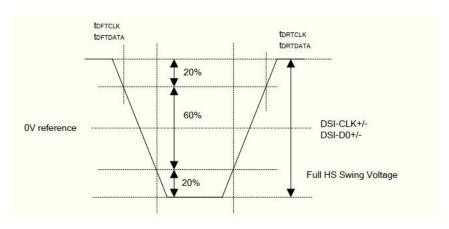
Note 1: VDDIO/VDDAM/VDDR =1.65 $\sim$ 3.6V, VCI=2.5 to 3.6V, VSSIO=DVSS=VSSA=VSSAM=VSSR =VSSB=0V, Ta=-30 to +85 °C.

Note 2: Dn=D0, D1, D2 and D3.





DSI clock channel timing

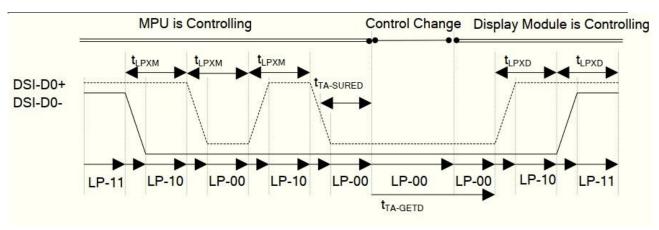


Rising and falling time on clock and data channel

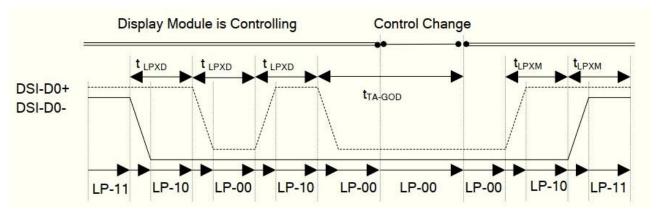
## Low Power Mode:

Signal	Symbol	Parameter	Min.	Тур.	Max.	Unit	Description
DSI-D0+/-	t <sub>LPXM</sub>	Length of LP-00, LP-01, LP-10 or LP-11 periodsMPU → Display Module	50	-	75	ns	Input
DSI-D0+/-	t <sub>LPXD</sub>	Length of LP-00, LP-01, LP-10 or LP-11periodsDisplay Module → MPU		75	ns	Output	
DSI-D0+/-	t <sub>TA-SURED</sub>	Time-out before the MPU start driving	t <sub>LPXD</sub>	648	2×t <sub>LPXD</sub>	ns	Output
DSI-D0+/-	t <sub>TA-GETD</sub>	Time to drive LP-00 by display module	5×t <sub>LPXD</sub>	925	721	ns	Input
DSI-D0+/-	t <sub>TA-GOD</sub>	Time to drive LP-00 after turnaround request - MPU	4×t <sub>LPXD</sub>	, <del>-</del>	-	ns	Output

Note 1:  $VDDIO/VDDAM/VDDR = 1.65\sim3.6V$ , VCI=2.5 to 3.6V, VSSIO=DVSS=VSSA=VSSAM=VSSR=VSSB=0V, Ta=-30 to +85 °C.



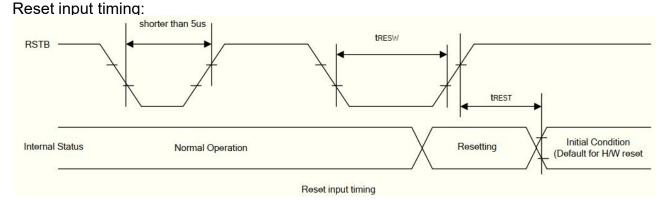
Bus Turnaround (BAT) from MPU to display module Timing



Bus Turnaround (BAT) from display module to MPU Timing



# 5.2 Display RESET Timing Characteristics



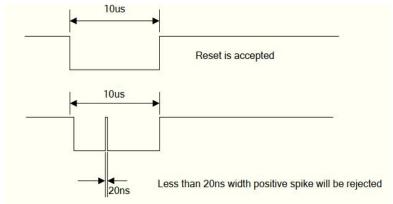
Signal	Symbol	Parameter	Min.	Тур.	Max.	Unit	Description
	tRESW	Reset "L" pulse width (Note 1)	10	-	85 <b>-</b> 8	μs	-
RSTB	tREST	tREST Reset complete time (Note 2)	-	2	5	ms	When reset applied during Sleep In Mode
			-	-	120	ms	When reset applied during Sleep Out Mode

Note 1: Spike due to an electrostatic discharge on RSTB line does not cause irregular system Reset according to the table below

RSTB Pulse	Action	
Shorter than 5µs	Reset Rejected	
Longer than 10µs	Reset	
Between 5µs and 10µs	Reset Start	

Note 2: During the Resetting period, the display will be blanked (The display is entering blanking sequence, which maximum time is 120 ms, when Reset Starts in Sleep Out –mode. The display remains the blank state in Sleep In–mode) and then return to Defaultcondition for H/W Reset.

Note 3: During Reset Complete Time, values in OTP memory will be latched to internal register during this period. This loading is doneevery time when there is H/W Reset complete time (tREST) within 5ms after a rising edge of RSTB. Note 4: Spike Rejection also applies during a valid Reset pulse as shown below:



Note 5: It is necessary to wait 5msec after releasing RSTB before sending commands. Also Sleep Out command cannot be sent for 120msec



## 6 Recommended Operating Sequence

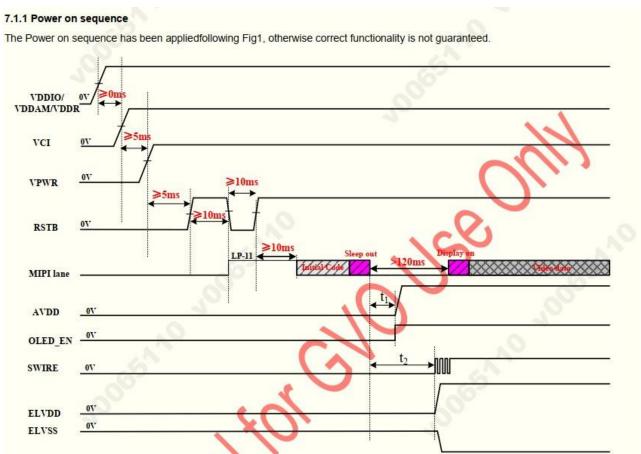
#### 6.1 Display Power on / off Sequence

During power off, if AMOLED is in the Sleep Out mode, VCI / VDDIO (VDDR, VDDAM) must be powered down minimum 120msec after RSTB has been released. During power off, if AMOLED is in the Sleep In mode, VCI / VDDIO (VDDR, VDDAM) can be powered down minimum 0msec after RSTB has been released.

Notes:

- 1. There will be no damage to the display module if the power sequences are notmet.
- 2. There will be no abnormal visible effects on the display panel during the Power On/Off Sequences.
- 3. There will be no abnormal visible effects on the display between end of Power On Sequence and before receiving Sleep Out command. Also between receiving Sleep In command and Power Off Sequence.
- 4. If RSTB line is not held stable by host during Power On Sequence as defined in section "power Level Mode", then it will be necessary to apply a Hardware Reset (RSTB) after Host Power On Sequence is complete to ensure correct operation. Otherwise function is not guaranteed.
- 5. There is not a limit for Rise/Fall time on VCI / VDDIO (VDDR, VDDAM).
- 6. The display module can also initialize and calibrate DSI-CLK+/- and DSI-D0+/- lanes within 10ms after LP-11 (Clock and Data Channels), VCI / VDDIO (VDDR, VDDAM) are applied and H/W Reset is not active (5ms is as same as the Reset Cancel Time).

#### 6.1.1 Power On Sequence



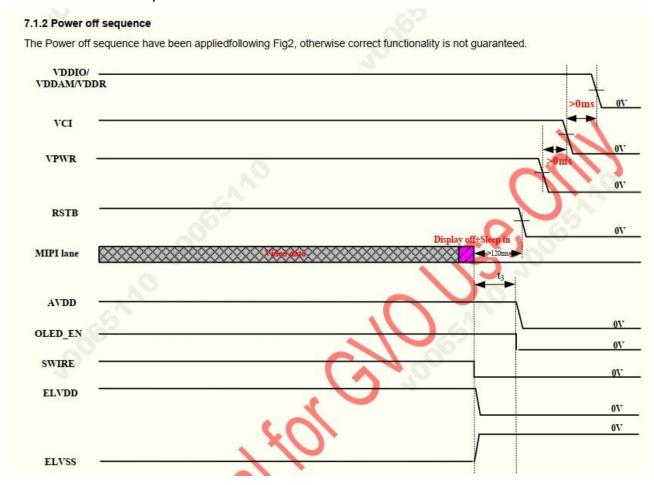
Note1: t1 is AVDD set up time, is controlled by AVDD ONT[7:0];

Note2: t2 is ELVDD/ELVSS set up time, is controlled by SWIRE ONF[5:0];



Note3: VPWR is the power of Power IC for AVDD/ELVDD/ELVSS;

## 6.1.2 Power Off Sequence



Note1: t<sub>3</sub> is Power off Delay time, is controlled by AVDD\_OFT[7:0]; Note2: VPWR is the power of Power IC for AVDD/ELVDD/ELVSS;



# 7 Touch Specification

# 7.1 General Specifications

NO	ITEM	SPEC	REMARK
1	Accuracy @D7mm Finger(mm)	center≤1.0mm border≤1.5mm	
2	Linearity @ D7mm Finger(mm)	center≤1.0mm border≤1.5mm	
3	Jitter @D7mm Finger(mm)	All≤1.0mm	
4	Sensitivity @D7mm Finger(mm)	w/o line broken	
5	Report rate	Typ: 120Hz Max: 240Hz	
6	Touch Point	Max 10 Fingers	

#### 7.2 Electrical Characteristics

## 7.2.1 Maximum Ratings

Item	Symbol	MIN	MAX	Unit
TP power supply Input	TSP_AVDD	2.7	3.6	V
TP power supply for logic circuits	TSP_VDDIO	1.7	3.6	V

## 7.2.2 Power supply DC characteristics

Item	Symbol	MIN	TYP	MAX	Unit
TP power supply Input	TSP_AVDD	2.8	2.8/3.0/3.3	3.6	V
TP power supply for logic circuits	TSP_VDDIO	1.7	1.8/TSP_AVDD	3.6	V

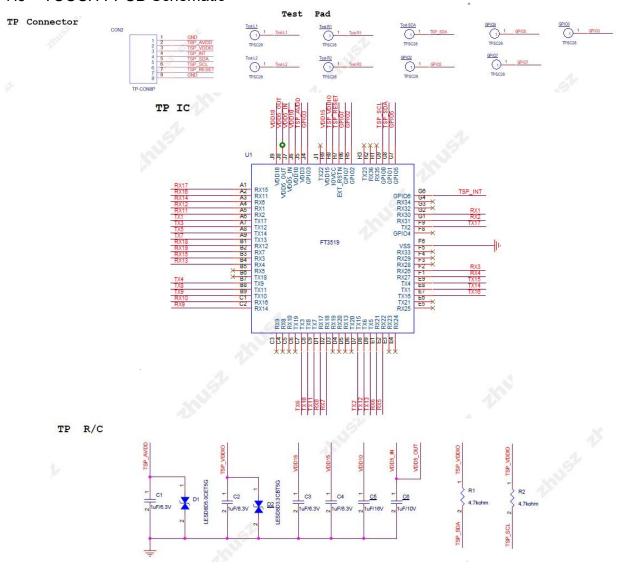
## 7.3 TP FPC Pin Assignment

No	Symbol	I/O	Description
1	GND	GND	Ground
2	TSP_AVDD	Power	Analog Power for Touch Panel
3	TSP_IOVCC	Power	Digital Power for Touch Panel
4	TSP_INT	0	Interrupt signal for Touch Panel
5	TSP_SDA	I/O	SDA pin for Touch Panel
6	TSP_SCL	I	SCL pin for Touch Panel
7	TSP_RESET	I	Reset Pin for Touch Panel
8	GND	GND	Ground

7.4 Touch Design

Item		Description	Notes
	Sensor structure	Oncell	
	Sensor pitch	Tx: 3.856mm,Rx:3.96mm	
Touch Design	Sensor pattern	Diamond	
	CH Number	17(Tx) / 19(Rx)	
	Trace mode	1T1R	

#### 7.5 TOUCH FPCB Schematic





# 7.6 TSP FPC Electronic Part List

Item	Reference	Specification
1	C1 C2 C3 C4	1uF/6.3V/0402
2	C5	1uF/16V/0402
3	C6	1uF/10V/0402
4	D1	Bi-directional /5V/0402
5	D2	Bi-directional /3.3V/0402
6	R1 R2	4.7ΚΩ/0402
7	U1	Touch IC ,FT3519



# 8 Optical Characteristics Optical Specification

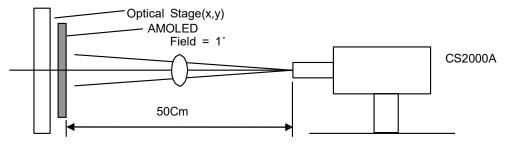
Item		Symbol	Condition	Min	Тур	Max	Unit	Remark
Luminan	се	L		450	500	550	Cd/m <sup>2</sup>	
	white	x		(0.279)	(0.299)	(0.319)		
	Wille	У		(0.2952)	(0.3152)	(0.3352)		
	Red	x		(0.650)	(0.680)	(0.710)		
Chromaticity		У		(0.285)	(0.315)	(0.345)		
Officinations	Green	x		(0.200)	(0.240)	(0.280)		
Blue	У		(0.670)	(0.710)	(0.750)			
	Rlue	x		(0.1133)	(0.143)	(0.173)		
	Dide	У		(0.016)	(0.046)	(0.076)		

#### **Test Conditions:**

- 1. The ambient temperature is  $25^{\circ}$ C.
- 2. The test systems refer to Note1 and Note2.

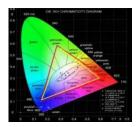
Note 1: Definition of optical measurement system.

The optical characteristics should be measured in dark room. The optical properties are measured at the center point of the AMOLED screen. All input terminals AMOLED panel must be ground when measuring the center area of the panel.



Note 2: Definition of color chromaticity (CIE1931)

Color coordinates measured at center point of AMOLED.





# 9 Environmental / Reliability Test

No	Test Item	Condition	Remark
1	High Temperature Operation	+70℃, 120hrs	IEC60068-2-2,GB2423.2
2	Low Temperature Operation	-20℃, 120hrs	IEC60068-2-1 GB2423.1
3	High Temperature Storage	+80℃, 120hrs	IEC60068-2-2 GB2423.2
4	Low Temperature Storage	-40℃, 120hrs	IEC60068-2-1 GB2423.1
5	High Temperature & High Humidity Operation	60℃, 90% RH,120hrs	IEC60068-2-78 GB/T2423.3
6	Thermal Shock (Non-operation)	-40(°C)/30(min) ~+80 (°C)/30(min), Change time:10min, 30Cycles	Start with cold temperature, End with high temperature, IEC60068-2-14,GB2423.22

Note: Product reliability items in the form of GK are used as reference items. The test results shall refer to the results of the reliability test of Visionox standards.



## 10 Quality Level

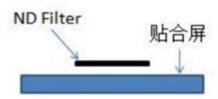
10.1 AMOLED Module of Characteristic Inspection

The environmental condition and visual inspection shall be conducted as below:
11.1.1 Test conditions: OLED is not light, cold white fluorescent lamp, illumination 1000 ±
200lux; OLED lighting source shall not be higher than 200lux, with black background around.

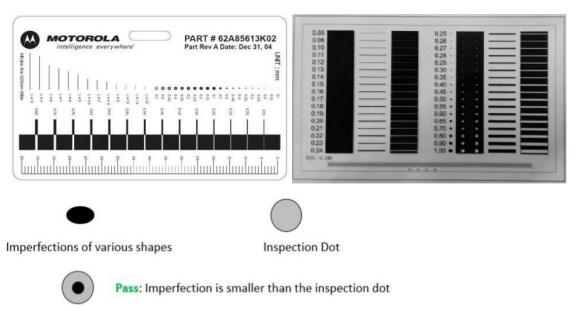
- 11.1.2 Inspection distance: the standard observation distance of all surfaces of the tested object is 30cm ±5cm.
- 11.1.3 Inspection angle: the angle between the product and the horizontal plane is 45°, and the eyes are perpendicular to the inspection plane. During inspection, the product needs to rotate 45° up, down, left and right. The observation line of sight needs to be within the half section of the cone. The observation angle is 45° with the vertical axis of the product apex. The central axis of the cone must be standard and perpendicular to the product surface and pass through the fluorescent lamp; For non-conventional display defects (including but not limited to local bright lines or local floodlights), the observation angle is 75 degrees from the normal of the product surface; Full visual angle of appearance.
  - 11.1.4 Inspection time: the inspection time without lighting is at least 10-12 seconds; The time of OLED lighting inspection for each picture is 1~3 seconds. If the defect is still not visible within the specified time, the inspection piece is deemed to be qualified.
  - 11.1.5 Test temperature: room temperature 15-35 °C, ambient humidity: 20-75% RH.
  - 11.1.6 Inspection tools:
  - 11.1.6.1 ND Filter: The ND Filter is placed at a distance of 2-3 cm above the defect for 2-3s to judge whether the defect is visible. As Figure below: (ND Filter is used to test mura isochromatic and light unevenness)







11.1.6.2 Point gauge (point gauge in the figure below is recommended), determination method: as shown in the figure, the point gauge film can cover is pass, and the point gauge film can not cover is Fail. For example, a maximum of 0.2mm same-color spot defect is allowed on the Class A surface, and the pass that can be covered by 0.2mm on the film. The one that can be covered is Fail.



11.1.6.3 Microscopic examination: use 20-50 times adjustable microscope and 10-30 times test eyepiece.

Fail: Imperfection is larger than the inspection dot

- 11.1.6.4 igital caliper: resolution 0.01mm.
- 11.1.6.5 Projector: anime microscope, 3D projector.
- 11.1.6.6 Judgment description



- 11.1.6.6.1 The measurement accuracy shall refer to the specification definition. When the measurement equipment accuracy is higher than the specification definition, the measured value needs to be rounded to the precision defined by the specificationthe. For example, the size of edge collapse is 0.20mm, and the thousandth is the reference position, which is rounded to 0.200mm~0.204mm is OK,>=0.205mm, it is judged as NG.
- 11.1.6.6.2 In addition to the tools used above, if additional inspection tools are needed to assist the judgment, they can only be carried out after the coordination of both parties.

#### 11.1.6.6.3 Bad code and definition

Cod	e and name	legend	explain
N L	Number  Length (mm)	-	Visually calculate the number; The statistics of the total number of defects does not include the completely "omitted" part. For the column defined as "omitted" and "omitted", it is not counted as the number of defects if it meets the requirements, otherwise it is calculated as an independent defect.  Dot line distinguishing rule: L is the long side, W is the short side  A. When L > 3W, handle as per line, otherwise
W	Width (mm)		handle as per point; B. When it is judged as line defect, S-shaped or C-shaped line appears, and the enclosed amount is less than 3/4 circle, it shall be treated as line defect; otherwise, it shall be treated as point defect, and the inner tangent circle shall simulate the size of point.
S	Area (mm2)	-	Surface gauge
D	Diameter (mm) D=(L+W)/2	-	Point diameter calculation: calculated by half of the sum of the long side and the short side, that is,



			D=(L+W)/2, where D represents the diameter of the point, L is the long side, and W is the short side;
Н	Depth (mm)	-	Digital micrometer
DS	Distance (mm)	DS DS	Distance between two points or between two lines
Schematic diagram of screen area		AAX GA K FAX OA	AA area: display area; GA area: GIP circuit area; FA area: Frit area; OA area: outside FA area
Leader area			Screen GIP circuit area, screen data circuit area
PAD Bangding District			COG/FOG Bonding alignment mark and Bonding Pad on LTPS substrate
PAD Non-state area			Screen test pad, cutting area and lead-free area on LTPS substrate
CT crimping area		CI DELLE CONTROL OF THE PARTY O	Pin end screen test pad



	等于1/2子會軍距回	A single sub-pixel (or red, or green, or blue) of one pixel is called a point; The definition of bright spot
		is that in the environment of 200 ± 50 Lux, the
Highlights		pixels or dots seen by employees with naked eyes
	華个完成	are always bright, and the bright spot is checked
		under the black screen
		A single sub-pixel (or red, or green, or blue) of one
		pixel is called a point; A dark point is defined as a
Scotoma		point that is not bright in a single sub-pixel seen
		with naked eyes in a 100% white picture under the
	单个暗点	environment of 200 ± 50 Lux.
Dark spot - two connection	暗点-二连接	Two adjacent sub-pixels under the magnifying glass are not bright at the same time (horizontal, vertical and oblique)
Dark Spot - Three Links	暗点三连接	The adjacent R, G and B sub-pixels under the magnifying glass are not bright at the same time (horizontal, vertical and oblique)
		AA: Front visible area, black ink internal area;
		A: Black ink area;
		B: Cover plate edge;
CG monomer area	з.—	The front defect that runs through the AA area and
division	y-	the A area shall be judged according to the
	正面 from side	specification of the strictest area, and the back
		defect shall be judged according to whether the
		AA area is visible.
Foreign matter		Due to the foreign matter in the polarizer, the
highlights	-	phenomenon that appears as a bright spot is called
		a foreign matter bright spot



point defect	L W	There are bright spots and black spots in local positions, including but not limited to the internal dirt of the screen itself, pinholes, serrations, concave-convex spots, color spots, tiny bubbles, white spots, stains on the fitting of the polarizer, poor polarizer itself and other spot-like defects. Point defects are judged by diameter.
Linear defect	L. w	Linear impurities in the screen, including filaments, fibers, polarizer fitting impurities in the screen, and scratches on the surface of polarizer, etc. Linear defects are judged by length and width.  Sensible scratch: also known as hard scratch, is a deep scratch on the surface, which is felt by hand.  Senseless scratch: also known as fine scratch, no deep scratch on the surface, no feeling when touching.
Serrated defect		W: Distance from sawtooth crest to trough
Edge collapse/angle collapse	Xu Yu Tu	In the process of screen production, especially in the process of molding and cutting, the small glass missing at the glass edge is caused.  X direction: parallel to FOG Pad or glass edge; Y direction: perpendicular to FOG Pad or glass edge; Z direction: screen thickness direction; T: The thickness of single-layer glass;
Pitting	-	In the unit area of 10mm * 10mm, the defect point with D $\leq$ 0.1mm, DS $\geq$ 2mm, and the number N $\geq$ 5. If the customer has other requirements, follow the customer's requirements.



		Including handprints, oil stains, fingerprints, stains,
		white fog and other undesirable phenomena. It is
		divided into erasable dirt and non-erasable dirt.
		Use a dust-free cloth dipped in alcohol, which can
		not be erased as non-erasable dirt. Wipable dirt is
		determined as follows:
Dirty	-	A. Dry dust-free cloth can be directly erased;
		B. Wipe with clean cloth dipped with anhydrous
		alcohol
		Press the alcohol-stained dust-free cloth on the dry
		dust-free cloth twice to absorb excess alcohol;
		Wipe back and forth with a dust-free cloth twice,
		and the dirt can be removed.

## 10.2 Sampling Procedures for Each Item Acceptance Table

Critical Defect (CR): any defect that directly or indirectly affects human health and safety, or the function of the product is lost.

Major Defect (MA): directly or indirectly affect the product function, or make part of the product function lost, and other customers do not acceptable defects.

Minor Defect (MI): appearance defect that does not affect product function and can be accepted by customers.

Defect Type	Sampling Procedures	AQL
Critical Defect (CR)	Take the normal inspection solution of the sampling plan of GB/T2828.1-2012 Inspection level Ⅱ	0.065
Major Defect (MA)	Take the normal inspection solution of the sampling plan of GB/T2828.1-2012 Inspection level Ⅱ	0.65
Minor Defect (MI)	Take the normal inspection solution of the sampling plan of GB/T2828.1-2012 Inspection level Ⅱ	1.0

10.3 Telecommunications Inspection Item

category	NO.	Inspection items	Inspection specification	test mode	defect type
	1	Display exception	not allow	visual	CR



Poor	2	No display	not allow	visual	CR
function	3	The picture flickers	not allow	visual	MA
TP function	4	TP test NG	not allow	visual	MA
	5	Bright dot	not allow	visual	MI
	6	Partial Bright dot	ND6% or reference limit sample	visual	MI
Dot	7	Dark dot	1.D≤0.15mm, ignored; 2.0.15mm <d≤ 0.2mm,="" ds<br="">≥ 10mm, N ≤ 10;3.D&gt; 0.2mm,not allowed;</d≤>	Visual inspection, Flinka	MI
	8	Bright line	not allow	visual	MA
Line	9	Dark line	not allow	visual	MA
	10	Slightly bright line	not allow	visual	MA
	11	horizontal mura	No control under W64/127 screen; The 4%ND Filter on the 255 screen determines that the invisible is OK and the visible is NG.	Visual ND Filter/limit sample	MI
	12	vertical mura	No control under W64/127 screen; The 4% ND Filter on the 255 screen determines that the invisible is OK and the visible is NG.	Visual ND Filter/limit sample	MI
Mura	13	White spot	No control under W64/127 screen; The 4% ND Filter on the 255 screen determines that the invisible is OK and the visible is NG.	Visual ND Filter/limit sample	MI
	14	Black spot	No control under W64/127 screen; The 4% ND Filter on the 255 screen determines that the invisible is OK and the visible is NG.	Visual ND Filter/limit sample	MI
	15	Color mura	4% ND Filter in W64/255 screen determines that the invisible is OK and the visible is NG	Visual ND Filter/limit sample	MI



	16	snowflake	No control under W64/127 screen; The 4% ND Filter on the 255 screen determines that the invisible is OK and the visible is NG.	Visual ND Filter/limit sample	MI			
	17	Twill mura	No control under W64/127 screen; The 4% ND Filter on the 255 screen determines that the invisible is OK and the visible is NG.	Visual ND Filter/limit sample	MI			
	18	Newtonian ring	No control under W64/127 screen; The 4% ND Filter on the 255 screen determines that the invisible is OK and the visible is NG.	Visual ND Filter/limit sample	MI			
	19	Uneven transition	Reference homogeneity standard to assist in judgment; The 4% ND Filter in the W64/255 screen determines that the invisible product is OK and the visible product is NG.	Visual ND Filter/limit sample	MI			
	<ol> <li>Mura all specify the screen judgment. For example, if the ELA mura judgment standard is 255, the ELA mura will only be judged on the W255 screen.</li> <li>Other types of mura have a low adverse effect rate and low incidence. According to the 4% ND Filter in the W64/255 screen, the invisible products are OK and the visible ones are NG.</li> </ol>							
Dot/line of foreign material	20	Dot/line defects (foreign material, black white dot, scratch, bubble, etc.)	Same point/line specifications	Visual inspection/Fli nka	MI			

10.4 Appearance Inspection Item

NO.	Inspection items	Surfac e Area	Inspection specification	test mode	defect type
1	Broken glass	AA/OA	not allow	visual	MA
2	crack	AA/OA	not allow	visual	MA
3	Edge collapse/cor ner	AA/OA	<ol> <li>Y ≤ 0.15mm, X and N are ignored;</li> <li>0.15<y 0.4mm,="" 2mm,="" ignored;<="" is="" li="" n="" x="" ≤=""> <li>Y&gt;0.4mm, not allowed;</li> <li>Z ≤ t, without damage to Frit body;</li> </y></li></ol>	Visual inspection, Flinka	MI



			Xu Tu		
4	flange	AA/OA	<ul><li>1. Y ≤ 0.2mm, X is uncontrolled;</li><li>2. Y&gt;0.2mm, not allowed;</li></ul>	Visual inspection, Flinka	MI
5	Glass warp	Whole area	The product is placed horizontally on the front and back, and the lifting height at one end (plug gauge) ≤ 0.6mm	Visual inspection, Flinka	MI
6	Pin dirty	Bongdi ng area	No control	visual	MI
7	Pin scratch	Bongdi ng area	Scratches and whitening are found by visual inspection, and need to be rechecked with a microscope. The broken lead is not allowed, and the overlap is not allowed  Note: CT pad area and pin non-bonding area are not controlled	visual	MI
8	PF film bump	LTPS	Touch is not allowed	visual	MI
9	PF film pinholes/pit s	LTPS	No control	visual	MI
10	PF film scratch	LTPS	<ol> <li>No scratch, no control; Scrape through, L&lt;10mm;</li> <li>The film shall be scraped through the exposed glass surface, referring to the lack of glue of PF film;</li> </ol>	Visual inspection, Flinka	MI
11	PF film lacks glue	LTPS	50> 5mm, W>5mm not allowed	Visual inspection, Flinka	MI
12	PF membrane is dirty	LTPS	Wipable dirt needs to be wiped, and non-wipe dirt refers to the color difference of PF film;	visual	MI
13	PF film overflow	LTPS	Edge overflow W<0.2mm, acceptable;     W>0.2mm, not allowed;	Visual inspection, Flinka	MI



14	Color difference/st ain (no convex touch)	LTPS	No control				visual	MI						
15	PF film gluing offset	LTPS	controlled	t for d by	the step 0.5 ± 0.2	area, th mm;		t shall be	Visual inspection, Flinka	MI				
16	Screen body is dirty	LTPS		nd e wip	the pola ped;	rizer of		dirt can be dirt cover	visual	MI				
			D (mm)	)	DS (r	mm)		cceptable number	\ <i>(</i> ''   1					
17	point defect	AA	D≤ 0.15mm	n	1			Ignore	Visual inspection,	MI				
			0.15mm <sup>-</sup> D≤0.2m		DS	≥10		N≤10	Flinka					
			W (mm	L	(mm)	DS (mm		Acceptab le number						
	Linear	gn matter AA	W≤ 0.03		L≤5	≥10	)	ignore						
18	defect/forei		AA	AA	AA	AA	AA	0.03< W≤ 0.05		L≤2	≥10	)	ignore	Visual inspection, Flinka
	inductive scratch		0.03< W≤ 0.05	2-	<l≪5< td=""><td>≥10</td><td>)</td><td>N≪4</td><td>Tillika</td><td></td></l≪5<>	≥10	)	N≪4	Tillika					
			W>0.0 5		-	/		Not allowed						
					L>5	/		Not allowed						
		Camer	D(	mm	)	Acce	ptabl	e number						
19	Point/Line	a hole area/Bli		€0.1			igno	ore	Visual inspection,	MI				
	defects	nd hole area	0.15<	0.15 <d≤0.2 ignore<="" td=""><td>ore</td><td>Flinka</td><td></td></d≤0.2>			ore	Flinka						
		Comer		D>0.2										
20	Newton rings (Blind hole area)	Camer a hole area/Bli nd hole area	Not control					Visual inspection	MI					
21	offset	Camer a hole	The meta	al rin	g extend	s inward	l 0.1r	mm ,ingore	Visual inspection	MI				



Blind hole color bias(same color)  Protective film scratch	area/Bli nd hole area Camer a hole area/Bli nd hole area Whole	Functional requirements such as transmittance and PV value are met,not	Visual	
color bias(same color)  Protective film scratch	a hole area/Bli nd hole area	transmittance and PV value are met,not	Visual	
film scratch	Whole	control appearance	inspection	MI
Don't a atting	area	No control under no hurt boby	Visual inspection	MI
Protective film starved/ove rflow glue/burr	Whole area	No control under no hurt boby	Visual inspection	MI
Dirt inside the protective film	Whole area	Not allowed	Visual inspection	MI
Easy to tear	Cover front	Function is invalid, damaged, leaked not allowed Wrinkles, bumps, dirt, punching bad, burr, overflow glue is not controlled	Visual inspection	MI
Polarizer edge overflow	AA	W≤0.35mm , Not control; W>0.35mm, Not allowed.	Visual inspection, Flinka	MI
Polarizer concave convex point	AA	convex point: D ≤ 0.2mm or refer to limit sample concave point: D≤3mm, DS≥10mm, N≤3or refer to limit sample	Visual inspection, Flinka	MI
Polarizer fold / indentation	AA	Does not affect the display as OK or refer to limit sample;	Visual inspection	MI
Polarizer chromatism	AA	No control	Visual inspection	MI
IC chip	IC	Not allowed	Visual inspection	MI
FPC body defect	FPC	<ol> <li>The parts on the FPC must be consistent with the product BOM table, and there are incorrect, multiple, or missing parts, which are not allowed; Polarities such as capacitors and inductors should not be soldered backwards or crooked;</li> <li>FPC scratches/scratches are based on the absence of exposed copper;</li> <li>Creases/Indentations: Indentations in the</li> </ol>	Visual inspection	MI
	rflow glue/burr Dirt inside the protective film  Easy to tear  Polarizer edge overflow Polarizer concave convex point Polarizer fold / indentation Polarizer chromatism IC chip	starved/ove rflow glue/burr  Dirt inside the protective film  Easy to tear  Polarizer edge overflow  Polarizer concave convex point  Polarizer fold / indentation  Polarizer chromatism  IC chip  FPC body  area  Whole area  AA  AA  AA  IC chip  FPC body  FPC	starved/ove rflow glue/burr  Dirt inside the protective film  Easy to tear  Cover front  Cover point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit sample  Concave point: D ≤ 0.2mm or refer to limit samp	starved/ove rflow glue/burr  Dirt inside the protective film  Easy to tear  Polarizer edge overflow 2 convex point:  Polarizer folid / indentation  Polarizer chromatism  IC chip  FPC body defect  PC  Dirt inside the protective area inspection  Not allowed  Not allowed  Function is invalid, damaged, leaked not allowed winkles, bumps, dirt, punching bad, burr, overflow glue is not controlled  Visual inspection  Visual inspection  Visual inspection  Visual inspection  Visual inspection  Visual inspection  Polarizer concave convex point: D ≤ 0.2mm or refer to limit sample  concave point: D ≤ 3mm, DS ≥ 10mm, N ≤ 3 or refer to limit sample;  Visual inspection, Flinka  Visual inspection  Flinka  Visual inspection  Visual inspection  Visual inspection  Visual inspection  Visual inspection  Visual inspection  Flinka  Visual inspection  Visual inspection  Visual inspection  Visual inspection  Flinka  Visual inspection  Visual inspection



34	connector  Insulating tape	connect or Bondin g area	deformation shall be controlled within 0.05mm; Does not affect the lighting function; Visual inspection of pin breakage, pin detachment, and deformation of the outer frame is not allowed;  There must be no obvious wrinkles or bubbles  1. Scratches and glue splashes are uncontrollable; 2. Do not wipe dirt or dirt; 3. The offset of the insulation tape should not	Visual inspection  Visual inspection	MI
			blackening, burns, or browning;  There should be no tin or residual solder beads on the connector, and there should be no tin connection on the connector pins; PIN		
33	FPC gold finger defect	Golden Finger Region	golden finger ≤ the line width;  2. Gold finger copper leakage: W ≤ 1/3 line width, L ≤ line width, unlimited quantity  3. Gold finger gap W1 ≤ 1/3 line width W, length L1 ≤ 1/2 line width W, unlimited quantity, all of the above conditions are met and allowed;  4. Gold finger pressure/scratch should not expose copper, there should be no unevenness, and there should be no depth visible to the naked eye, which does not affect assembly and is acceptable;  5. Gold fingers should not have sharp creases or dead folds;  6. FPC gold fingers should not have oxidation,	Visual inspection	MI
			covering film to turn white; Non line area indentation should not cause FPC damage  4. Except for the golden finger. FPC foreign object: a. Spot shape: D ≤ 0.5mm, N ≤ 3; b. Linear: length and width ≤ 0.3 * 5mm;  1. Golden finger cracking: The length and width of the crack/damage at the top of the golden finger. ≤ the line width:		



36	Composite tape	All	5. Damaged, incomplete, or missing labels are not allowed;  1. It is not allowed for the composite tape to leak out of the edge of the screen body;  2. Folding of composite tape, light leakage during assembly, or affecting assembly and thickness are not allowed;  3. Damaged composite tape is not allowed;  4. The size of the composite tape cutting defect does not meet the requirements of the drawing and cannot be controlled;  5. Composite tape should not be wiped with dirt or foreign objects, and foreign objects should follow the dotted line standard;  6. The burrs of the composite tape should not exceed the edge of the screen body, regardless of control;  8. Composite adhesive tape with no control over glue splashes or overflow;  9. Composite tape bubbles: D ≤ 5mm, N not included;  10. Composite tape bumps: acute angle bumps D ≤ 0.3mm, N ≤ 3;  11. Composite tape foreign object (foreign object between copper foil and blue film): D ≤ 0.3mm, N ≤ 3;  12. Edge sawtooth of composite tape: 0.5 * 3mm, N ≤ 3;  13. The color difference of the protective film in the composite tape is not controlled;  14. Copper foil indentation and dead bending in composite tape are not allowed, which does not affect assembly and thickness control; Or reference limit sample;  15. No control of foreign objects/dents in copper foil in composite tape;	Visual inspection	MI
37	OCA overflow	All	Not allowed within AAarea; Externally visible: Control standard ≤ 0.15mm	Visual inspection	MI



38	Sealing glue	Pin	<ol> <li>Broken adhesive is not allowed, and the circuit cannot be exposed.</li> <li>The thickness of the colloid shall not be higher than the POL surface.</li> <li>Bubble diameter&lt;1mm.</li> <li>Other: According to the drawings and work instructions.</li> </ol>	Visual inspection	MI
39	Conductive cloth	All	<ol> <li>Conductive cloth dirt: D ≤ 5mm, N ≤ 2;</li> <li>Conductive cloth bubbles: D ≤ 2mm, N ≤ 2;</li> <li>Conductive cloth foreign object: D ≤ 1mm, N ≤ 3;</li> <li>Folding of conductive fabric: N ≤ 2;</li> </ol>	Visual inspection	MI
40	Copper foil	All	Copper foil sticking is not allowed to leak out of the edge of the screen body; Abnormal color of copper foil refers to standard samples/sealed samples, and damage is not allowed. Soft scratches on the surface are not controlled.	Visual inspection	MI
41	QR code	QR code	It is not allowed to be unable to scan or difficult to scan (recognition can only be achieved after three consecutive scans), with a clear appearance, no blurring, missing printing, and other defects	Visual inspection	MI
42	Package	Other	Products should put into the anti-static trays, with non-overlapping, and the trays should be staggered placed.  Different products cannot be mixed into the same inner package.  The package should not have obvious deformation or breakage .The printing labels type and quantity are correct.  The package should have QC signature. ROHS label is needed if the product is under ROHS control.	visual	-
43	Boundary dimension NG	Other	It is not allowed to exceed the dimensional tolerance required by the specifications and drawings	Calipers, measuring instruments	-



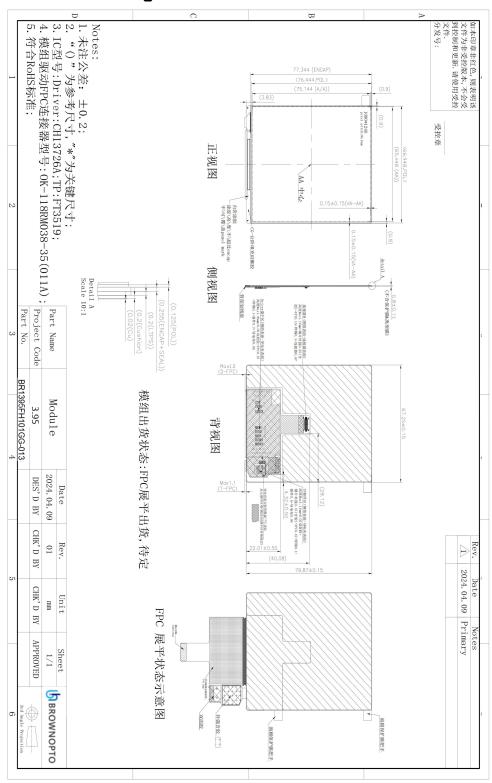
10.5 Inspection picture library

Serial number	picture Picture name Mainly judged as defect		Mainly judged as defective	remarks
1		W_ GRAD(64) 64 gray scale	Point/line type, foreign matter point/line, mura type	/
2		W_ GRAD(128) 128 gray scale	Point/line type, foreign matter point/line, mura type	1
3		WHITE white	Point/line type, foreign matter point/line, mura type	1
4		Black black	Bright spot, bright line, dark mura	1
5		RED red	Point type, line type, foreign matter point/line	1
6		GREEN green	Point type, line type, foreign matter point/line	1
7		BLUE blue	Point type, line type, foreign matter point/line	1

Note: The actual sequence and lock seconds of the screen can be adjusted according to the customer's requirements and the needs of the factory.



# 11 Mechanical Drawing



Shenzhen Brownopto Technology Co.,LTD



### 12 Precautions for Use of AMOLED Modules

- 12.1 Handling Precautions:
- 12.1.1 The display panel is made of glass. Do not subject it to a mechanical shock by dropping it from height.
- 12.1.2 Do not press down the screen or the adjoining areas too hard because the color tone may be shifted.
- 12.1.3 The polarizer covering the display surface of the AMOLED module is soft and easily scratched. Handle this polarizer carefully.
- 12.1.4 If the display surface is contaminated, blow on the surface and gently wipe it with a soft dry cloth. If it is still not completely clear, moisten the cloth with ethyl alcohol.
- 12.1.5 Solvents may damage the polarizer. Do not use water, ketone or aromatic solvents except ethyl alcohol.
  Do not attempt to disassemble the AMOLED Module.
- 12.1.6 If the logic circuit power is off, do not apply the input signals.
- 12.1.7 To prevent destruction from static electricity, be careful to maintain an optimum working environment.
- 12.1.8 Be sure to make yourself in contact with the ground when handling with the AMOLED Modules.
- 12.1.9 Tools required for assembly, such as soldering irons, must be properly ground.
- 12.1.10 To reduce the generation of static electricity, do not conduct assembly or other work under dry conditions.
- 12.1.11 To protect the display surface, the AMOLED Module is coated with a film. Be careful when peeling off this protective film, because static electricity may generate.
- 12.2 Storage Precautions:
- 12.2.1 When storing the AMOLED modules, be sure that they are not directly exposed to the sunlight or the light of fluorescent lamps.
- 12.2.2 The AMOLED modules should be stored under the storage temperature range. If the AMOLED modules will be stored for a long time, the recommended condition is: Temperature: 0°C~40°C Relatively humidity: ≤80%
- 12.2.3 The AMOLED modules should be stored in the room without acid, alkali or harmful gas.
- 12.3 Transportation Precautions:
- 12.3.1 The AMOLED modules should not be suffered from falling and violent shocking during transportation. Besides, excessive press, water, damp and sunshine, should be avoided.